Title: TEST BOARD [illegible]E-EMBEDDING METHOD TO IMPRO[illegible]RF MEASUREMENTS ACCURACY O[illegible]N AUTOMATIC TESTING EQUIPM[illegible] FOR IC WAFERS

Inventors: Giuseppe Di Gregorio et al. Express Mail No.: EL755716868US Docket No.: 856063.678

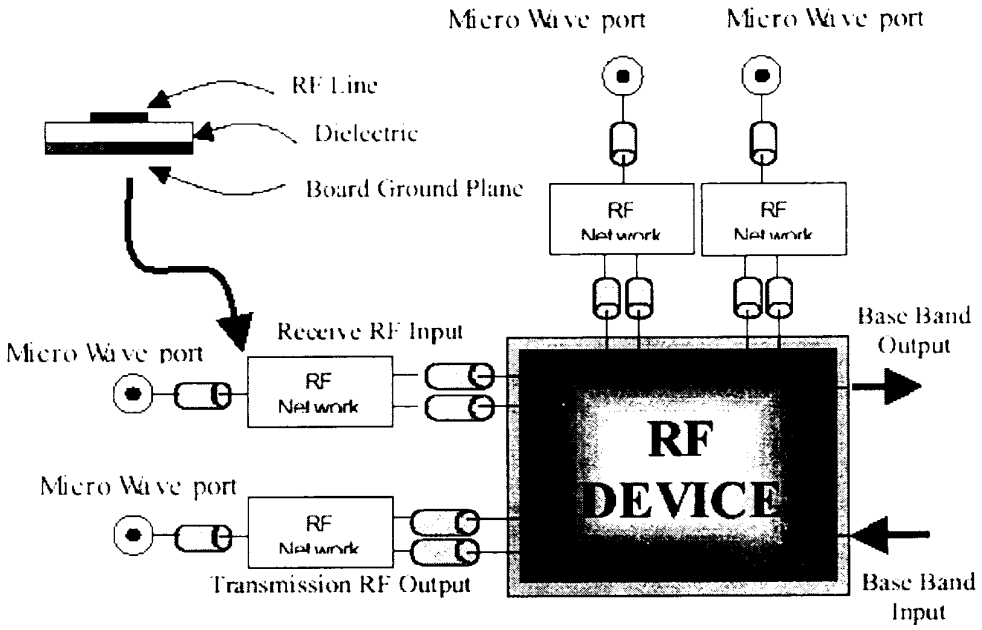

FIG. 1

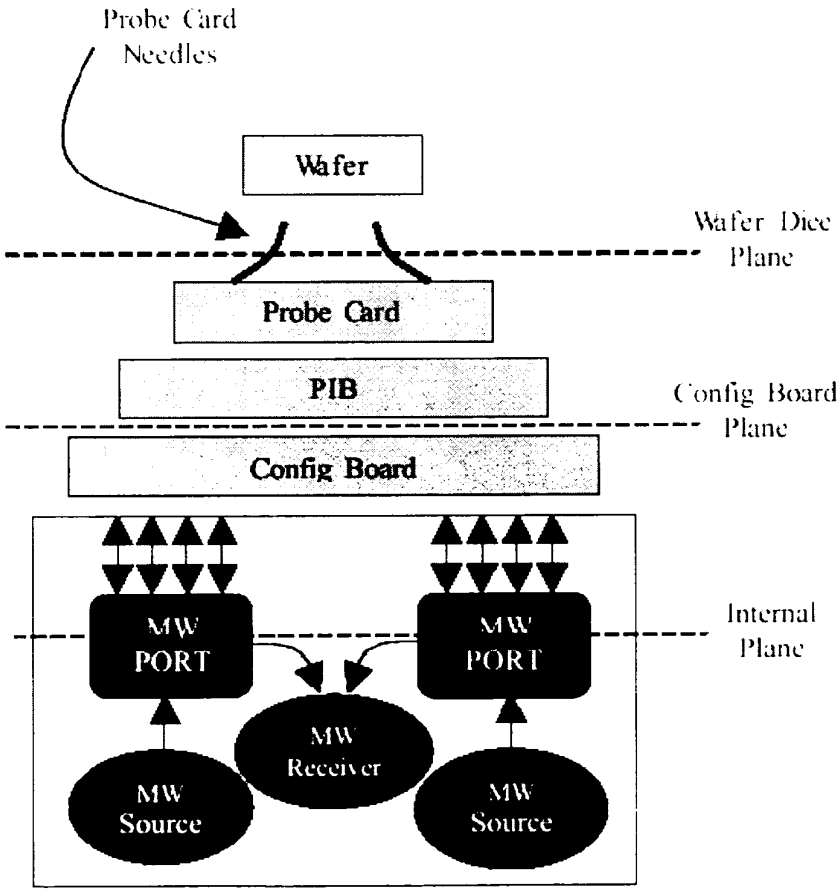

FIG. 2

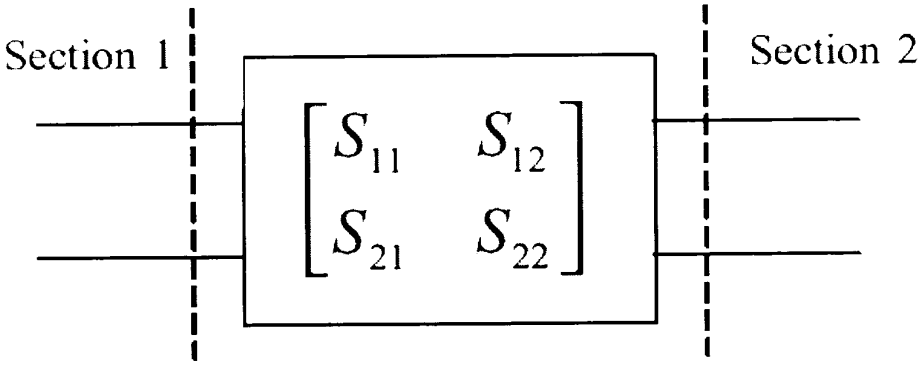
Section 1
Section 2
$\begin{bmatrix} S_{11} & S_{12} \\ S_{21} & S_{22} \end{bmatrix}$

FIG. 3

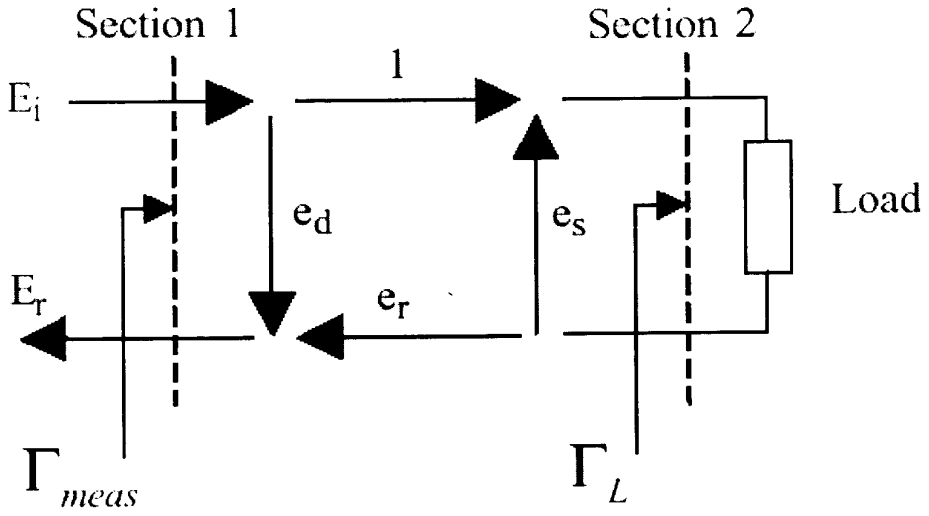
Section 1
Section 2
1
E_i
e_d
e_s
Load
E_r
e_r
Γ_{meas}
Γ_L

FIG. 4

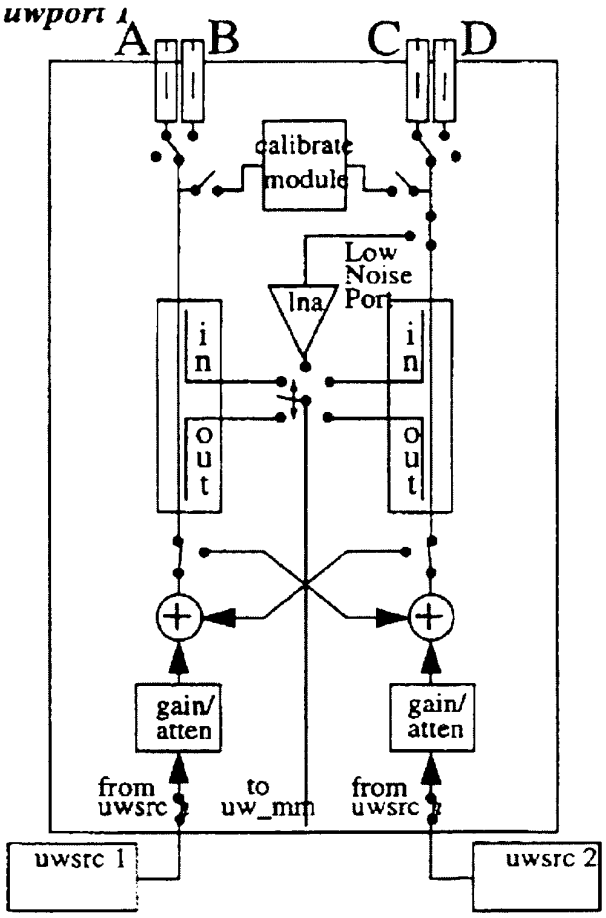
uwport 1
A
B
C
D
calibrate module
Low Noise Port
lna
in
out
in
out
gain/ atten
gain/ atten
from uwsrc 2
to uw_mm
from uwsrc 2
uwsrc 1
uwsrc 2

FIG. 5

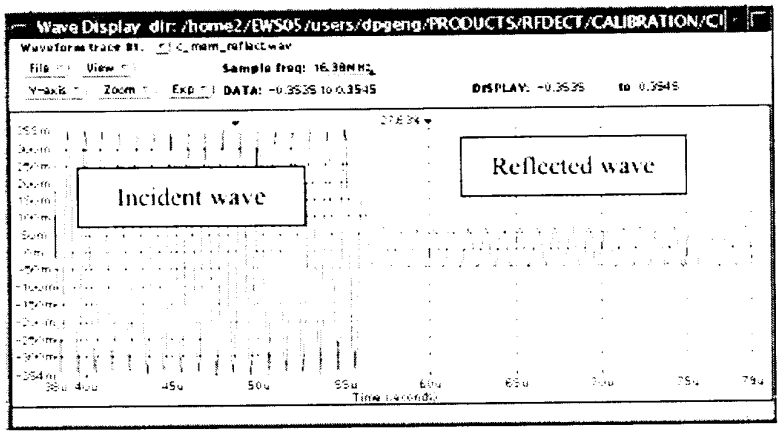
Wave Display dir: /home2/EWS05/users/dpgeng/PRODUCTS/RFDECT/CALIBRATION/CI
Incident wave
Reflected wave

FIG. 6

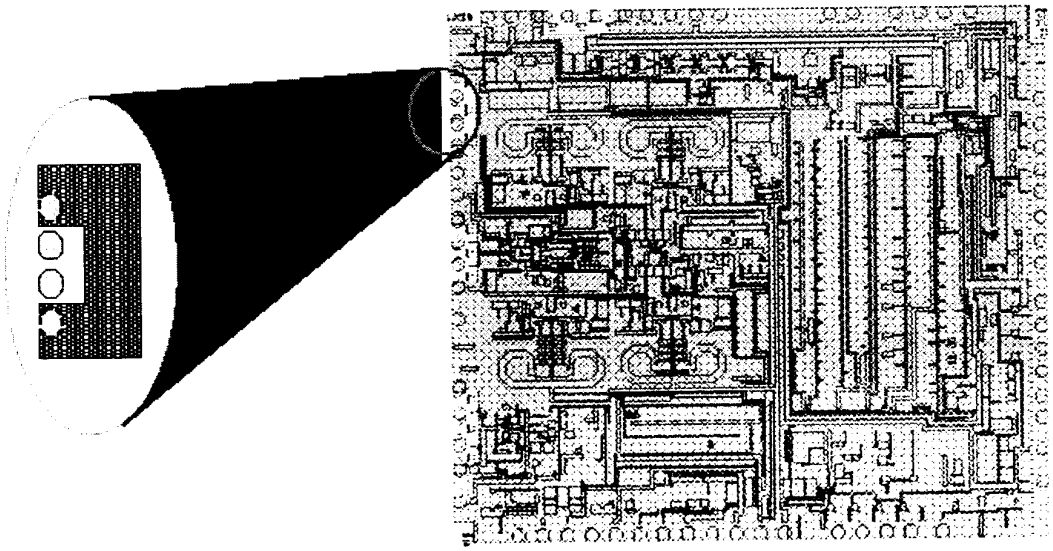

FIG. 7

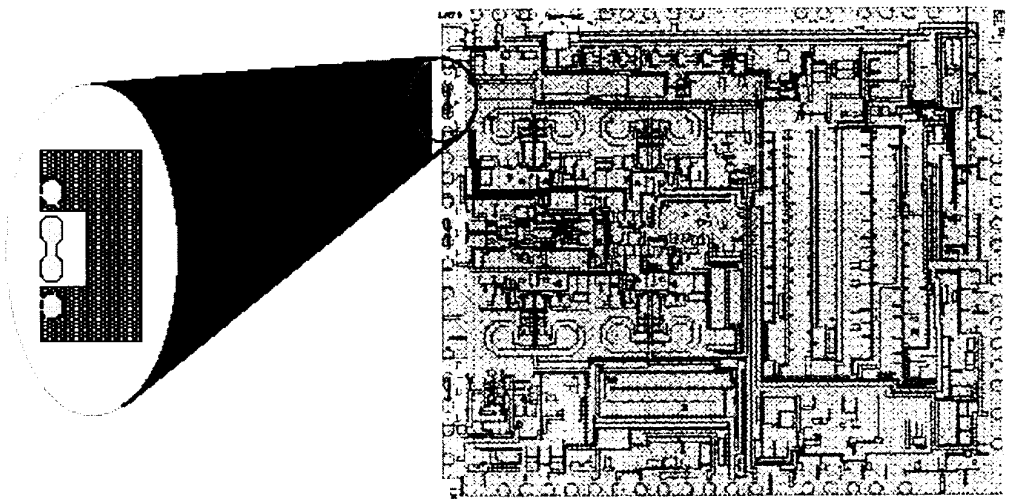

FIG. 8

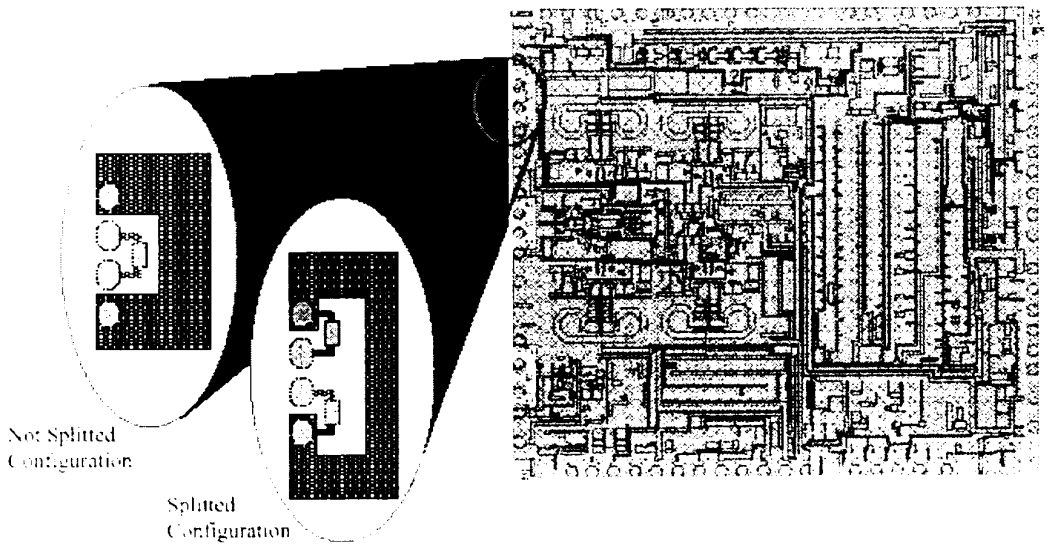

FIG. 9

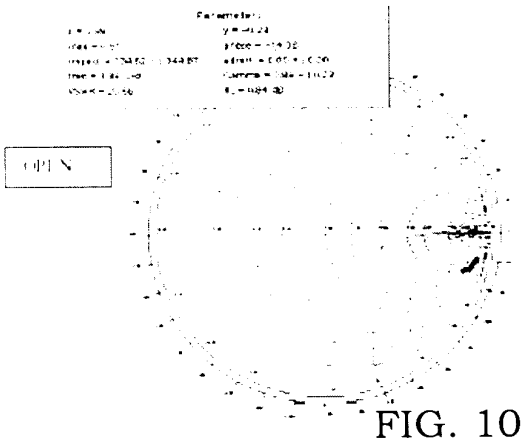

FIG. 10

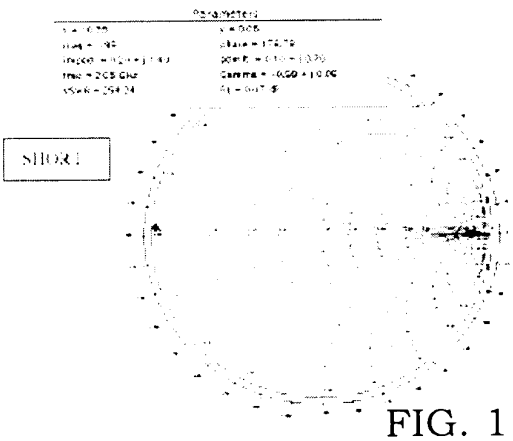

FIG. 11

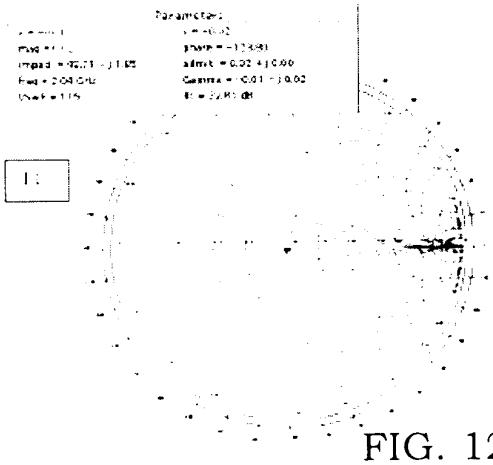

FIG. 12

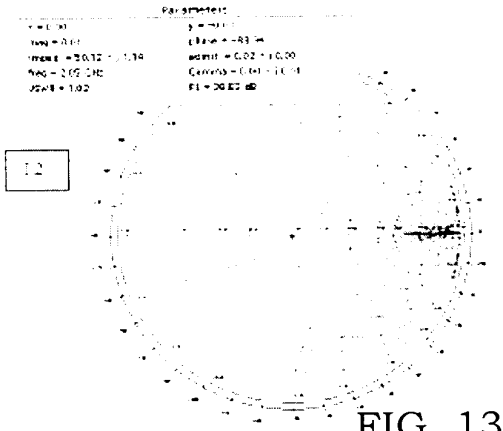

FIG. 13

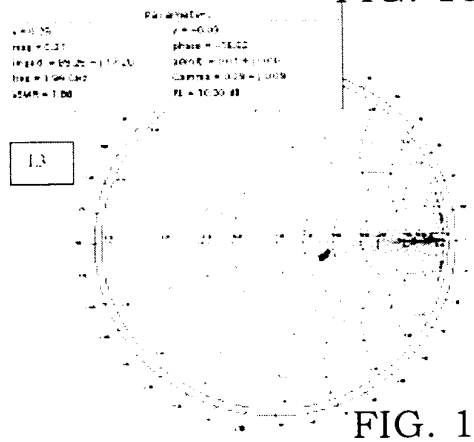

FIG. 14

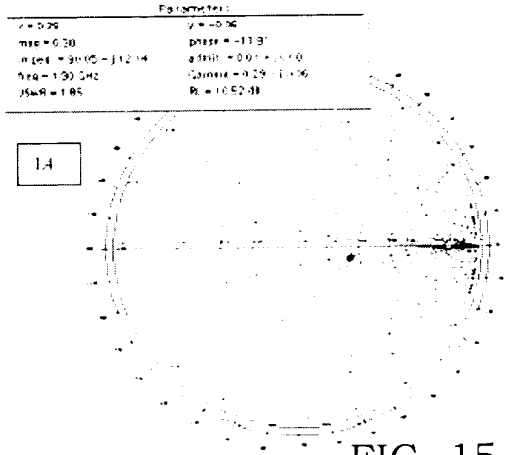

FIG. 15

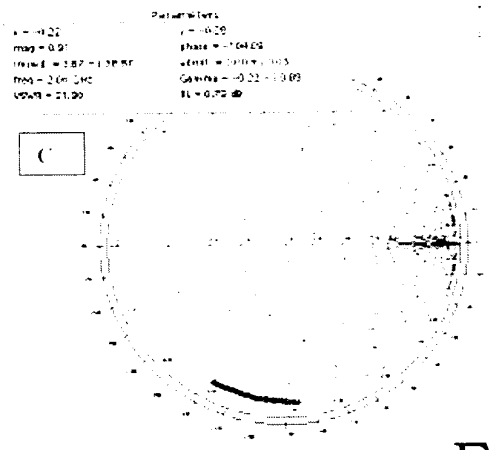
C

FIG. 16

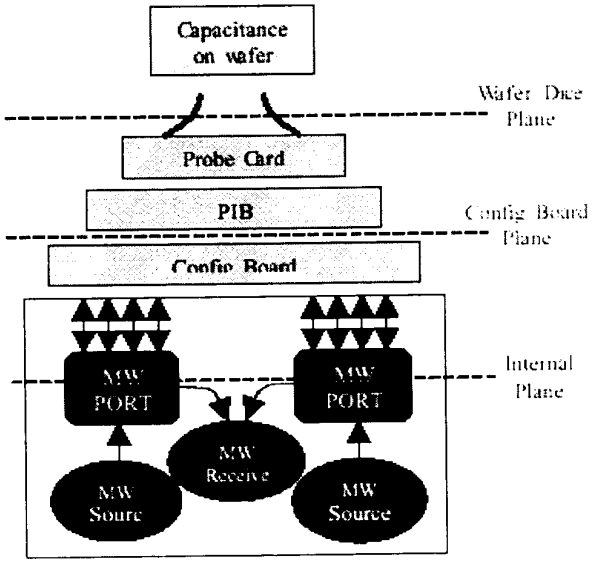
Capacitance on wafer
Wafer Dice Plane
Probe Card
PIB
Config Board Plane
Config Board
MW PORT
MW PORT
Internal Plane
MW Receive
MW Source
MW Source

FIG. 17

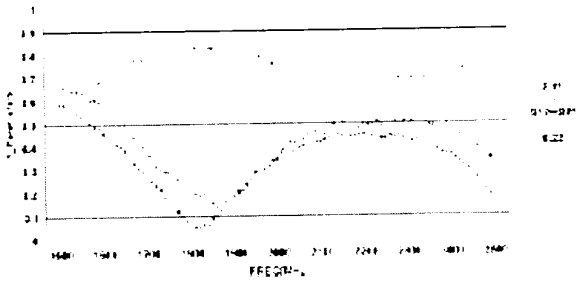

FIG. 18

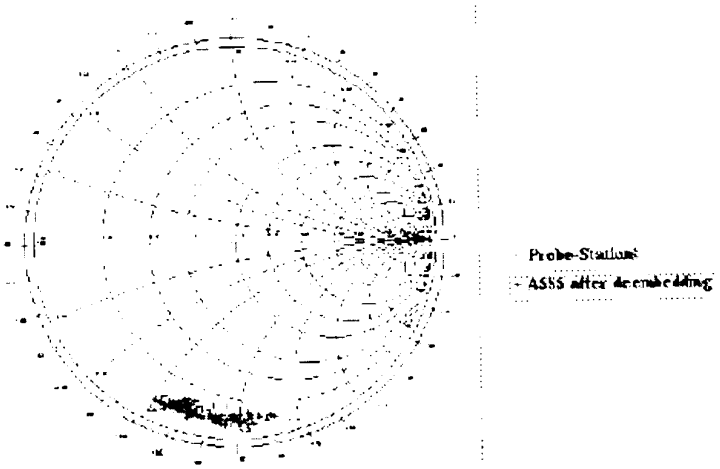

FIG. 19

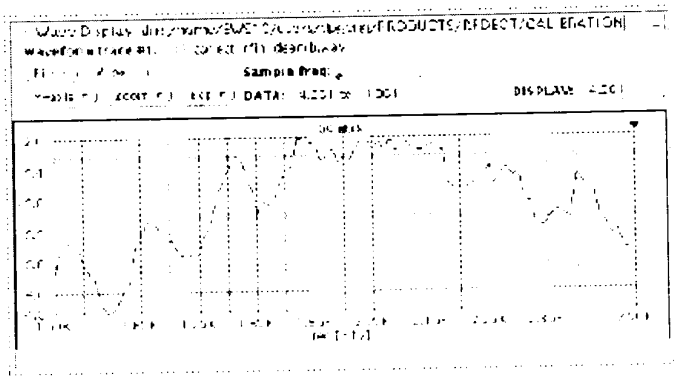

FIG. 20

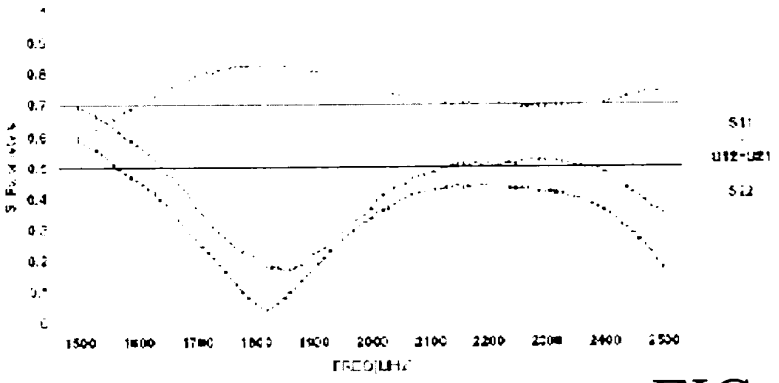

FIG. 21

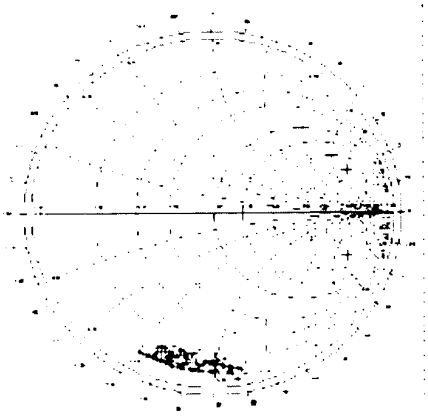

FIG. 22

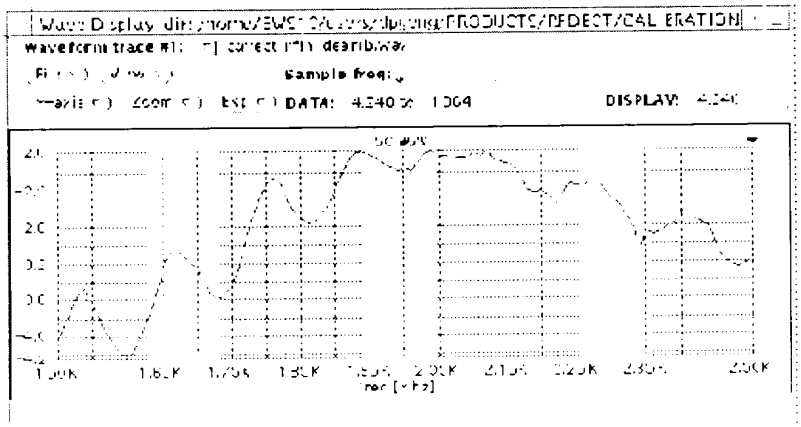

FIG. 23

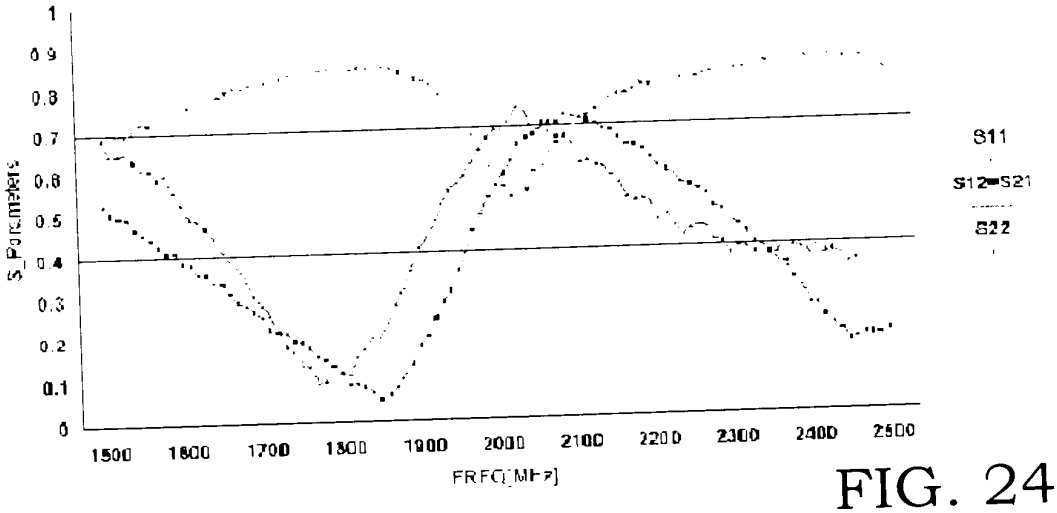

FIG. 24

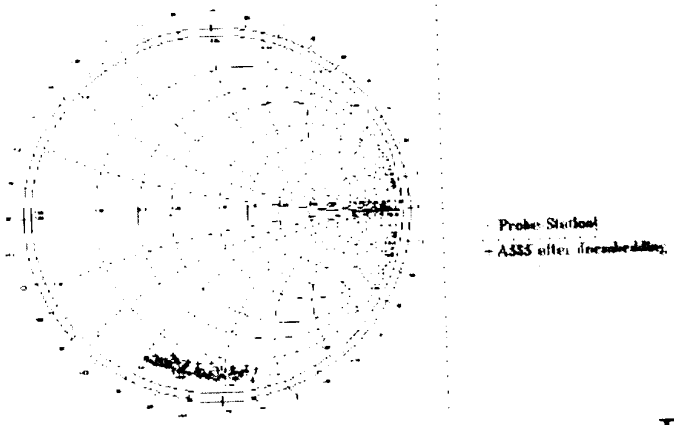

FIG. 25

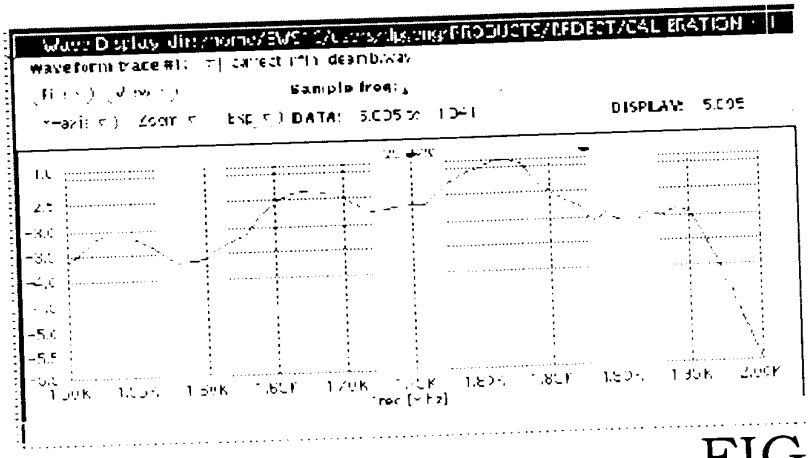

FIG. 26

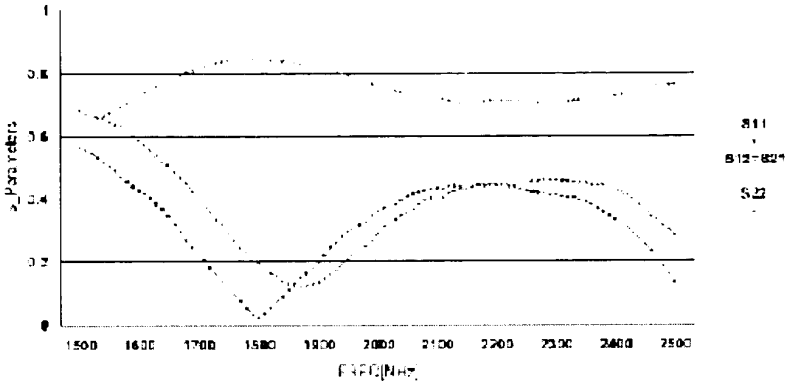

FIG. 27

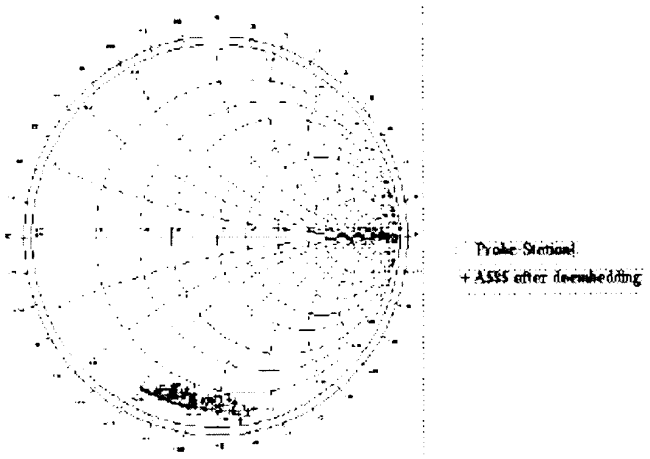

FIG. 28

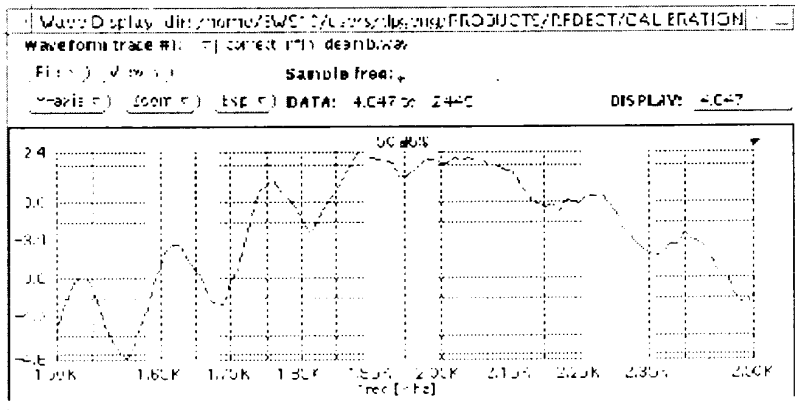

FIG. 29